



Datasheet – epc902, epc903, epc904, epc905

CCD line sensor with 128 / 256 / 512 pixel

General Description

The epc902..905 (sometimes herein after designated as epc90x) are high-performance CCD line sensor, embedded in a CMOS framework. Thus, they are solid state CCD/CMOS imagers. The epc90x are derivatives of the epc901 line imager chip and offer higher speed with one line of 128, 256 or 512 pixels, compared to the epc901 chip with 1024 pixels. All imagers have in common that they can store a total of up to 4 frames in the frame store for ultra high-speed image acquisition (fast acquisition / slow read out). They all have in common a high performance video amplifier (single ended / differential) analog output for highest SNR. This allows the user to select his interface of choice.

The acquisition of the image is automatically controlled by a hardware control signal. Once the acquisition is completed, the imagers set a ready signal. The transmission of the frame is controlled by the external control signal READ. When a read-out is initiated by a pulse on the READ signal, it is sampled by a CDS stage. After a fixed delay the frame can be shifted out through the video amplifier by applying the appropriate number of read clock edges.

The device offers various configuration options:

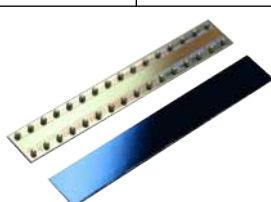
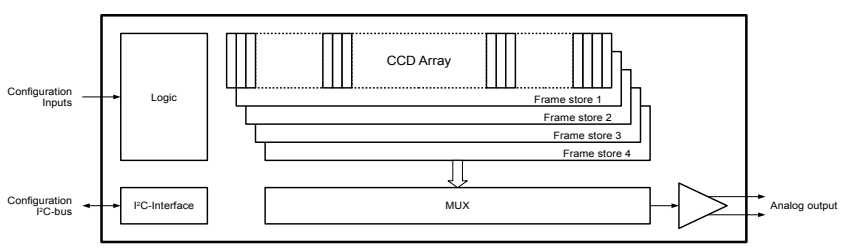
- Gain of the read-out stage selectable of 1, 2 or 4
- Transmission direction left to right and right to left
- Single- or multi-frame acquisition
- Clearing of frames stored and periodic flushing of pixel array to avoid blooming

Features

- Very high frame rate
- Photosensitive CCD array backside illuminated
- Very high sensitivity
- Pixel length of 120µm, various pixel pitch
- On-chip correlated-double sampling (CDS)
- Single-ended or differential analog output
- Simple 5-pin control interface for acquisition and read-out
- I2C bus interface
- Internal clock source, trimmable
- Two on-chip temperature sensors
- Single supply voltage
- 32 Pin space saving CSP package
- Chip size L x W x T: 8.0 x 1.3 x 0.23 mm

Applications

- Linear and rotary encoder
- Triangulation light barrier / distance measurement
- Line sensor / camera
- Surface scan
- Multi-touch displays / electronic white boards
- Spectrometers
- Bar code readers

Product selector	epc902	epc903	epc904	epc905
Pixel field	512	256	256	128
Pixel pitch (µm)	15	30	15	30
Output mode	Differential	Differential / single ended	Differential	Differential / single ended
Array length (mm)	7.68	7.68	3.84	3.84
Frame rate (fps @25% magnitude)	73,000	92,000	125,000	143,000
Package				
Block diagram				

Preliminary

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1. Block diagram

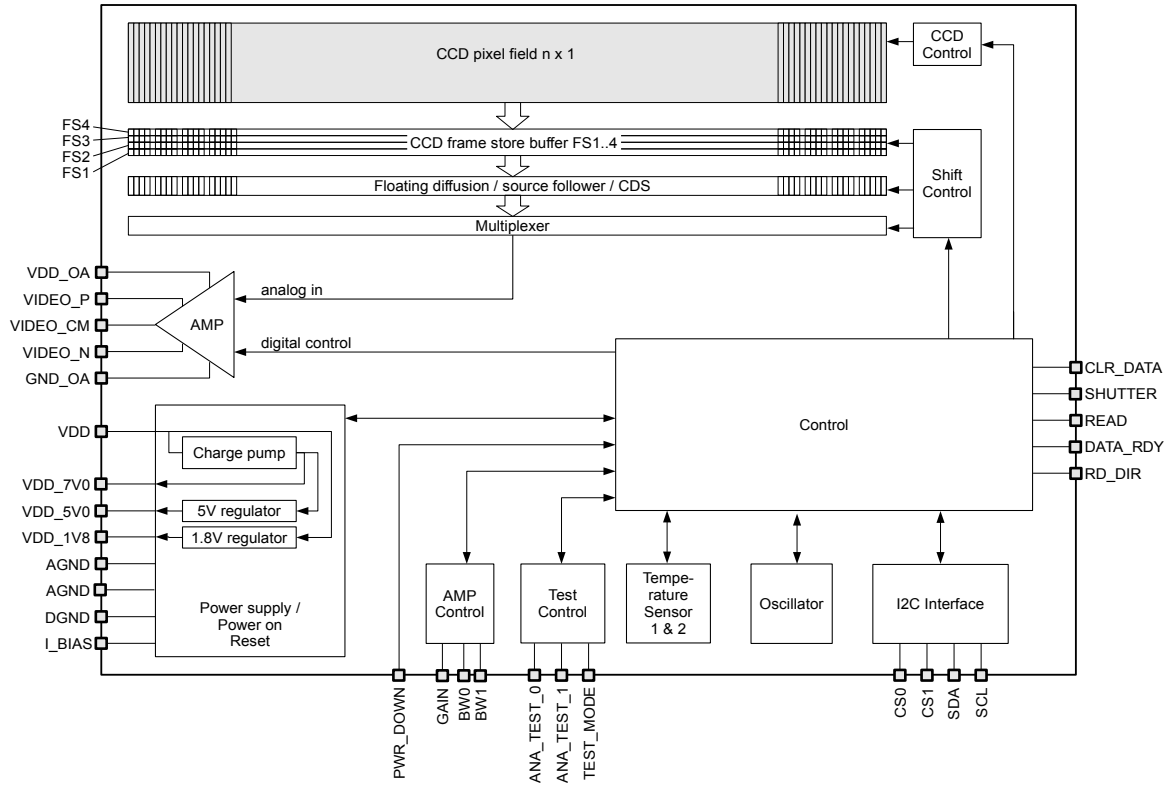


Figure 1: Block diagram

2. Pin-out

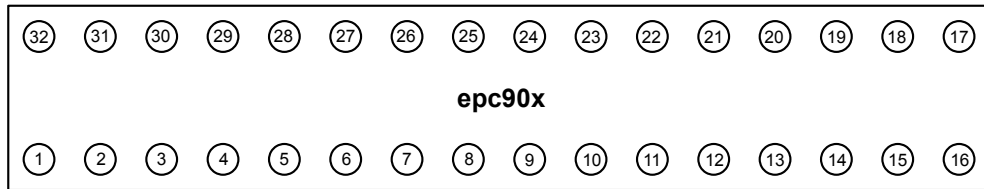


Figure 2: Pin-out, view to the photo-sensitive side (top-view)

Pin no.	Pin name	Pin type	Default [V]	Description			
				epc902	epc903	epc904	epc905
Digital pins							
2	PWR_DOWN	DI	0	Power-down mode enable			
3	CLR_DATA	DI	0	Clear internal data memory controller			
5	CLR_PIX	DI	0	Rising edge resets pixels and its controller			
6	SHUTTER	DI	0	Exposure active when SHUTTER set			
12	READ	DI	0	Read-out control and read clock			
4	DATA_RDY	DO		Flag when data on video interface is ready. Used as a strap pin to turn on/off the charge pump			
13	SDA	DIOD	VDD	I2C serial data (open drain)			
14	SCL	DIOD	VDD	I2C serial clock (open drain)			
15	MOD_R	DI	model dependent	0	0	VDD	VDD
17	CS1	TER	VDD/2	I2C chip select 1			
19	CS0	TER	VDD/2	I2C chip select 0			
21	GAIN	TER	VDD/2	Select gain of read-out path			
22	BW0	TER	VDD/2	LSB of bandwidth of video amplifier			
23	BW1	TER	VDD/2	MSB of bandwidth of video amplifier			
24	RD_DIR	DI	0	Read-out direction			
25	MOD_B	DI	model dependent	0	VDD	0	VDD
30	TEST_MODE	DI	0	Chip test			
Analog pins							
8	VIDEO_N	AO		Negative terminal of video output			
9	VIDEO_P	AO		Positive terminal of video output			
11	VIDEO_CM	AI	VDD/2	Voltage to set video output common-mode			
27	I_BIAS	AI		Bias current			
28	ANA_TEST_1	AIO	0	Analog test in-/output 1			
29	ANA_TEST_0	AIO	0	Analog test in-/output 0, rising edge indicates the last pixel in a frame			
Supply pins							
26	VDD	Supply		Positive chip supply voltage			
10	VDD_OA	Supply		Positive supply of video amplifier			
32	VDD_1V8			Decoupling			
18	VDD_5V0	AO / Supply		Decoupling / external 5V supply for low power consumption (refer to 10.2)			
20	VDD_7V0			Decoupling			
16	AGND	Supply		Analog ground			
1	AGND	Supply		Analog ground			
7	GND_OA	Supply		Video amplifier ground			
31	DGND	Supply		Digital ground			

Definitions:

- DI: Digital input pin, with an internal pull-down resistor of approx. 100-250kΩ
- DO: Digital output pin
- DIOD: General purpose bidirectional digital pin with open-drain output, requires external pull-up resistor
- AO: Analog output
- AI: Analog input
- AIO: Analog input and output
- TER: Ternary input pin, with a pull-down and an equal pull-up resistor of approx. 100-250kΩ which tie the pin to the VDD/2 state.

2.1. Power domains

The epc90x chip has internally 5 different power domains and 3 ground references which are interconnected with ESD protection diodes. All pins are also equipped with ESD protection diodes. Figure 3 shows this functional circuit. The diodes have a breakthrough voltage of 0.3V. The designer has to take care that none of these diodes become conductive either at power-up, power-down or normal operation.

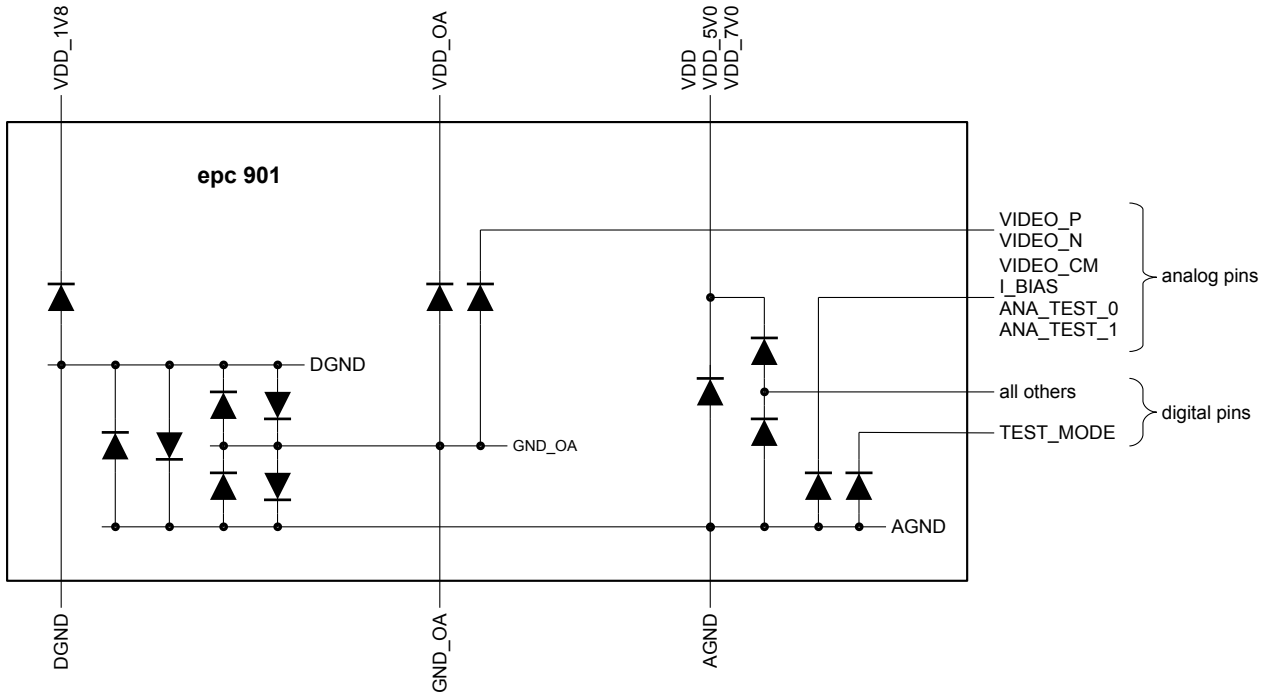


Figure 3: ESD protection diode circuit

3. Electrical, optical and timing characteristics

($T_A = 25^\circ\text{C}$, $V_{DD} = 3.0\text{V}$ unless otherwise noted)

3.1. Electrical and other characteristics

Parameter	Description	Min	Typ	Max	Unit	
V_{DD} Nominal	Nominal supply voltage on VDD and VDD_OA	2.70	3.00	3.45	V	
	Supply voltage on VDD and VDD_OA with Read Clock of max. 1 MHz.	2.45				
PSRR	Power supply rejection ratio VDD and VDD_OA.	Differential		13	dB	
		Single ended		9	dB	
$I_{DD} + I_{DD_OA}$ ¹	Total current consumption on pins VDD and VDD_OA (refer to section 10)					
	Differential mode, full video bandwidth ² , max. fps Charge pump: ON Temperature sensors: ON	Idle mode (READ = L)		26	39	mA
		Peak, during read-out		48	72	mA
	Differential mode, full video bandwidth ² , max. fps external VDD5V0 supply ³ Charge pump: OFF Temperature sensors: OFF	Idle mode (READ = L)		10	15	mA
		Peak, during read-out		16	24	mA
	Differential mode, low video bandwidth, 1kfps ⁴ , external VDD5V0 supply ³ Charge pump: OFF Temperature sensors: OFF	Idle mode (READ = L)		6.0	9.0	mA
		Peak, during read-out		6.0	9.0	mA
	Single-ended mode, low video bandwidth, 1kfps ⁴ Charge pump: ON Temperature sensors: ON	Idle mode (READ = L)		21	30	mA
		Peak, during read-out		40	60	mA
	Single-ended mode, low video bandwidth, 1kfps ⁴ , external VDD5V0 supply ³ Charge pump: OFF Temperature sensors: OFF	Idle mode (READ = L)		5.0	10.0	mA
		Peak during read-out		5.0	10.0	mA
Power-Save mode (POWR_DOWN = H, shutter still working), external VDD5V0 supply ³ Charge pump: OFF Temperature sensors: OFF			1.3	2	mA	
In-rush current at power-up during approximately 5ms Charge pump: ON			60	90	mA	
In-rush current at power-up during approximately 2ms, external VDD5V0 supply ³ Charge pump: OFF			50	75	mA	
I_{DD_5V}	Current consumption on pin VDD_5V0 ³ , Differential/single-ended mode, full video bandwidth, max. fps ² external VDD5V0 supply ³) Charge pump: OFF		1.2	2.5	mA	
V_{DIL}	Low voltage level on binary digital inputs ⁵ (Level L)			$0.2 \cdot V_{DD}$	V	
V_{DIH}	High voltage level on binary digital inputs ⁵ (Level H)	$0.5 \cdot V_{DD}$			V	
V_{DOL}, V_{TERIL}	Low voltage level on binary and ternary digital outputs (Level L)			$0.2 \cdot V_{DD}$	V	
V_{DOH}, V_{TERIH}	High voltage level on binary and ternary digital outputs (Level H)	$0.8 \cdot V_{DD}$			V	
V_{TERIM}	Centre voltage level on ternary digital inputs (Level M)	$0.4 \cdot V_{DD}$		$0.6 \cdot V_{DD}$	V	
I_{DI}	Sink current at digital inputs			10	μA	
R_{DI}	Internal pull-down resistor	100		250	k Ω	
R_{TER}	Internal voltage dividing resistors which force the input to VDD/2	100		250	k Ω	
I_{DO}	Sink / source current at digital outputs			3	mA	
V_{VDD1V8}	Internally generated voltage on pin VDD1V8	1.62	1.8	1.98	V	
V_{VDD5V0}	Internally generated voltage on pin VDD5V0	4.5	5.0	5.5	V	
V_{VDD7V0}	Internally generated voltage on pin VDD7V0	6.0	6.5	7.0	V	
$V_{VIDEO_P_N}$	Voltage range at output of video amplifier (@ gain 1)	0.25		$V_{DD} - 0.25$	V	
V_{CM_SE}	Voltage at VIDEO_CM to select single-ended mode			0.4	V	

Parameter	Description	Min	Typ	Max	Unit
V _{CM,D}	Common-mode voltage in differential mode, set on pin VIDEO_CM. Note: For V _{CM,D} >1V, differential mode is detected automatically by default. For V _{CM,D} <1V, differential mode has to be enabled by setting bit AMP_OVR in register FORCE_ANA_CTRL_SIGS (see section 8)	0.5	V _{DD} /2	V _{DD} /2+0.1	V
R _{IN,CM}	Input resistance of VIDEO_CM	100			kΩ
CMRR _{CM}	Common-mode rejection ratio on VIDEO_CM (f ≥ 100 kHz)	100kHz ... 50MHz	17		dB
		100kHz ... 10MHz	24		dB
V _{OFF,VIDEO,CM}	Common-mode offset of video amplifier output			±50	mV
V _{OFF,VIDEO,SIG}	Signal offset of video amplifier output			±100	mV
C _{LVIDEO}	Load capacitance on video output	single ended	5	100	pF
		differential	5	25	pF
R _{INT,VIDEO}	Output resistance of the video amplifier	single ended		32	Ω
		differential		11	Ω
R _{LVIDEO}	Load resistance on video output	3			kΩ
R _{th J-A}	Thermal resistance junction - ambient		65		K/W

Notes:

¹ The current values change with the first Read Pulse after boot-up to these values

² Video amplifier BW = HIGH_BW, VIDEO_GBW_SEL_REG = 0x3

³ VDD5V0 has only to be supplied externally in case the charge pump is configured to be off. See section 10.2

⁴ Video amplifier BW = LOW_BW, VIDEO_GBW_SEL_REG = 0x0.

⁵ I2C pins SCL and SDA are according to I2C standards

3.2. Temperature sensor characteristics

Parameter	Description	Min	Typ	Max	Unit
T _{TEMP}	Temperature measurement range	-40		+85	°C
OFFSET _{TEMP}	Temperature sensor offset		-10.1·10 ³		LSB
GAIN _{TEMP}	Temperature sensor gain. The typical measured temperature value of e.g. the left temperature sensor can be calculated from the value of the sensor output registers TEMP_SENS_L_MSB and TEMP_SENS_L_LSB as follows: $T_{TEMP,L} = \frac{TEMP_L[12:0] - OFFSET_{TEMP}}{GAIN_{TEMP}} \quad [K]$ For accurate measurements, calibration is required.	24	48	96	LSB/K
P _{TS}	Resolution of the temperature sensors		13		bits
N _{TEMP}	Noise		2	4	LSB
LIN _{TEMP}	Linearity of temperature sensors over the full temperature range		±2	±4	K
f _{TEMP}	Update rate of the temperature sensors (configurable)	0.1		10	Hz

3.3. Timing parameters

Parameter	Description	Min	Typ	Max	Unit	
T _{STARTUP}	Start-up time after applying external supply/supplies (includes ramp-up of charge pump)			10	ms	
T _{CP_UP}	Charge pump power-up time: time from changing the bit CP_PD from 1 to 0 until chip is operational (internal VDD5V)			5	ms	
T _{WAKE_UP}	Wake-up time from Power-Save mode		7	12	µs	
f _{OSC}	Oscillator clock frequency at nominal trim value (OSC_TRIM_REG at default value), refer to section 6.3	room temperature	22.4	36	48	MHz
		-20°C < T _A < 65°C	18	36	50 ^{3,4}	MHz
T _{SU,CONF}	Setup time of configuration pins with respect to rising edge of read pulse	50			ns	
T _{H,CONF}	Hold time of configuration pins with respect to rising edge of read pulse	3			Oscillator clock cycles	

Parameter	Description	Min	Typ	Max	Unit
T _{SHUTTER}	Pulse width of SHUTTER signal	5			Oscillator clock cycles
T _{FLUSH}	Flush period ¹	30		32	Oscillator clock cycles
T _{SHIFT}	Shift period ¹	24		26	Oscillator clock cycles
T _{RD_PULSE}	Pulse width of Read Pulse	3			Oscillator clock cycles
T _{CDS}	CDS operation			37	Oscillator clock cycles
T _{STORE}	Duration how long a frame may be stored in the frame-store	10			ms
f _{READ}	READ clock rate ²	0.1		54	MHz
D	READ clock duty cycle @ f _{READ} max	45	50	55	%
T _{H,VIDEO}	Period during which the output of the video amplifier is held stable after the last read clock edge		50		µs
T _{PERIOD,FLUSH}	Periodicity of the periodic flush operation ⁵		100		ms
T _{PULSE,CLR_DATA}	Pulse width on CLR_DATA	3			Oscillator clock cycles
B _{3dB,VIDEO}	3dB-bandwidth of video output @ C _{LVIDEO} = 40pF	10	11		MHz

Notes:

¹ The duration of the flush and shift periods can be calculated exactly by measurement of the clock oscillator frequency (see section 6.3)

² To achieve the maximum clock frequency, the duty cycle of the read clock has to be 50% with a maximal tolerance of ±5%.

³ The oscillator shall not be trimmed to a frequency higher than 50MHz.

⁴ Max. frame rate is achieved at max. f_{OSC}

⁵ Refer to section 5.5 for more details.

3.4. Absolute maximum ratings

Description	Conditions
Power supply voltage (VDD)	-0.3V to +5V
Voltage to any Pin	-0.3 to VDD +0.3V
Operating and storage Temperature Range (T _s)	-40°C to +85°C
Relative humidity	0 to 95% non-condensing
ESD rating	all pins except VDD7V0 vs. VDD1V8: HBM class 2 (2kV to <4kV, JEDEC) Pin VDD7V0 vs. VDD1V8: HBM class 1B (500V to <1kV, JEDEC) Note: Pin VDD7V0 is in the final circuit loaded with 2.2µF low ESR capacitor.

3.5. Optical characteristics

(Gain = 1, video bandwidth = 1MHz, differential mode, T_A = 25°C)

Parameter	Description	Min	Typ	Max	Unit	
W _{PIX}	Width of pixels	epc902, epc904		15.0	µm	
		epc903, epc905		30.0	µm	
H _{PIX}	Height of pixels		120.0		µm	
N _{PIX}	Number of pixels	epc902		512		
		epc903, epc904		256		
		epc905		128		
N _{FS}	Number of frames stored on-chip (including the pixel array)		4			
FF	Optical fill factor in pixel array		100		%	
CG	Conversion gain	3	5	8	µV/e-	
S _v	Optical sensitivity (λ = 630 nm, gain 4)		284		V/(Lux*s)	
FW ⁴	Full-well capacity per frame	400			ke-	
M _{FW}	Irradiance to generate FW electrons per pixel in 1 ns (λ = 630 nm)		155		mW/mm ²	
N _{READ_D}	Read noise, differential mode, optimal settings ¹		500	1,000	µVrms	
N _{READ_SE}	Read noise, single ended mode, optimal settings ¹		350	700	µVrms	
LIN	Linearity ²	Differential mode		1.0	2.0	%
		Single-ended mode		2.0	4.0	%
I _{LAG}	Image lag @ max. V _{pp} and 400ke-	Single-frame acquisition (see section 5.2)			0.2	%
		Multi-frame acquisition (see section 5.3)		0.2	0.5	%
δV _{DARK,PIX}	Output voltage drift due to dark current in pixel area		2.0	10.0	V/s	
δV _{DARK,FS}	Output voltage drift due to dark current in frame store area		0.1	0.3	V/s	
Θ _{DARK}	Thermal drift of dark current	Doubles approx. every 8°K				
PRNU ³	Photo response non-uniformity (@ 0.5*FW ⁴)		2	6	%	
DSNU ³	Dark pixel non-uniformity @ T _{EXP} = 100 µs		±0.3		% FW	
	Surface reflectivity (@ 550 to 860 nm)	0° incident angle		2	%	
	Surface reflectivity (@ 550 to 860 nm)	30° incident angle		4	%	
	Pixel cross-talk (@ 630nm, 0° incident angle) ⁵	epc902, epc904		10	%	
		epc903, epc905		5		

Table 1: Optical specification

Notes:

¹ Charge pump and temp sensor off, video amplifier BW=LOW_BW, VIDEO_GBW_SEL_REG=0x0 (minimum video amplifier bias current, Read Clock 1MHz).

² The linearity is defined as the maximum deviation of the pixel responses between 10% and 80% FW⁴ from the straight line between 10% and 80% FW⁴. Pixels with high dark current excluded.

³ Valid for Pixel:

epc902:	2 .. 510
epc903/904:	2 .. 254
epc905:	2 .. 126

⁴ FW corresponds to 2V swing at the output in differential mode.

The typical quantum efficiency as a function of wavelength is shown in Figure 4. It is based on standard AR coating, optimized for 750nm.

Customization possible:

Wavelength optimized versions are available upon request.

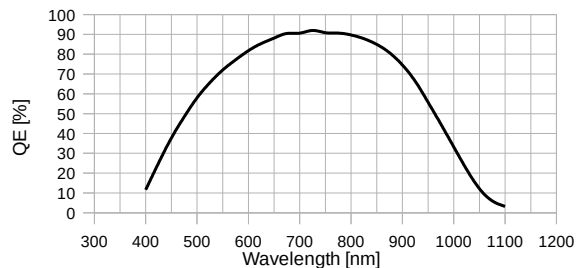


Figure 4: Typical quantum efficiency (QE) as a function of wavelength

3.6. Frequency response

The signal amplitude at the output of the video amplifier is a function of the optical modulation and the read-out clock frequency. The optical modulation is defined as follows:

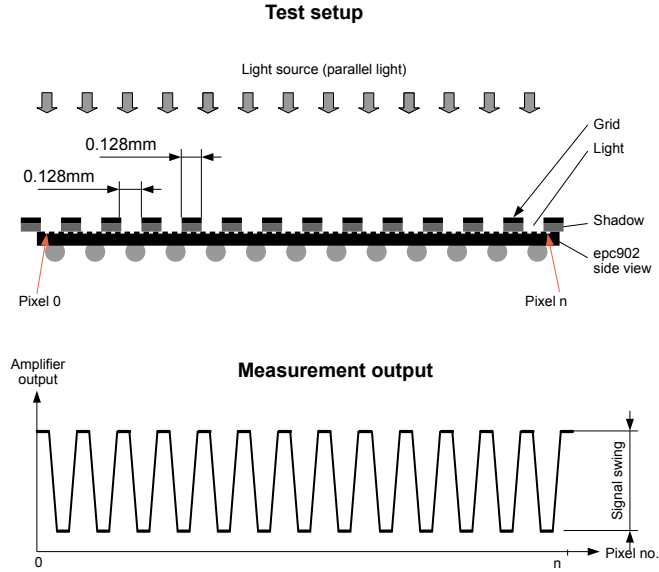


Figure 5: Modulation measurement

The amplitude at the video amplifier output as a function of the Read Clock frequency is as follows (temperature sensor off, differential mode):

Read Clock frequency	BW (video amplifier bandwidth setting)	VIDEO_GBW_SEL_REG	GAIN	Signal swing	SNR typ. (charge pump off)		SNR typ. (charge pump on)	
					min	typ	min	typ
1MHz	LOW_BW	0x0	1	2.0Vpp	66dB	70dB	65dB	67dB
10MHz	HIGH_BW	0x3	1	1.5Vpp	55dB	58dB	53dB	55dB
54MHz	HIGH_BW	0x3	1	0.5Vpp	46dB	49dB	44dB	46dB
54MHz	HIGH_BW	0x3	2	0.75Vpp	46dB	49dB	42dB	46dB
54MHz	HIGH_BW	0x3	4	1.25Vpp	46dB	49dB	42dB	46dB

Table 2: Useful video amplifier signal swing and SNR for different settings

3.7. Video amplifier frequency response

The following Bode plot shows the typical frequency response of the readout chain, according to the settings of the configuration pins BW0 and BW1, refer to section 4 and Table 8.

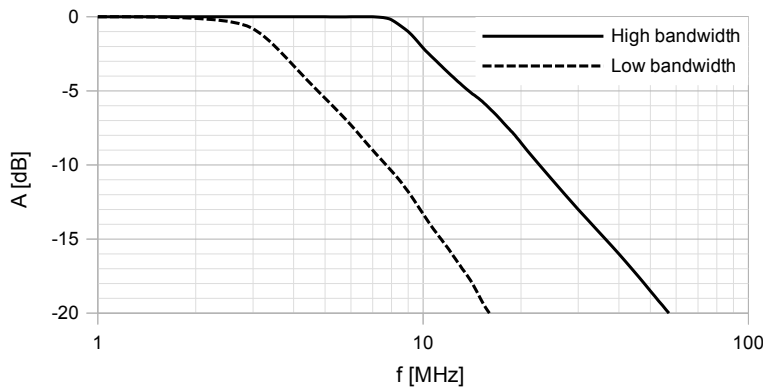


Figure 6: Typical frequency response

4. Configuration

The configuration pin status at power up and after reset define the operating parameters (hardware setting, refer to Table 3). The operation parameters can be changed during runtime over I2C (software setting, refer to 8). Shaded field are used in typical applications.

Pin Name	Low (GND)	High-Z	High (VDD)	Comments
RD_DIR	Pixel 0 .. nn		Pixel nn .. 0	nn: highest pixel number
GAIN	2	1	4	Gain multiplier
VIDEO_CM	n/a	On	n/a	Refer also to section 9.1
DATA_RDY	Charge pump on	N/A	Charge pump off	Refer to Figure 8

BW0		X		16 MHz	The video bandwidth values are approximative only. The video bandwidth affects the current consumption and the noise at the output. The lower the bandwidth the lower the noise and the lower the current consumption. Recommendation: Keep the bandwidth as low as possible.
BW1		X			
BW0			X	8 MHz	
BW1	X				
BW0	X			4MHz	
BW1			X		
BW0			X	1MHz	
BW1			X		

Table 3: Configuration pin description (gray shaded cells are recommended, typical settings)

Notes:

- The configuration pins can be changed during runtime. Their status is read with the rising edge of the READ signal (Figure 7):

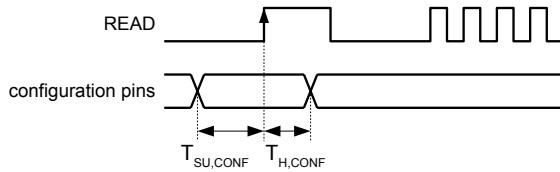


Figure 7: Status change of the configuration during runtime

- VIDEO_CM and DATA_RDY are not read with the rising edge of the READ signal
- RD_CONF_CTRL has to be at 0 (see Table 12).

- Enable/disable the charge pump:

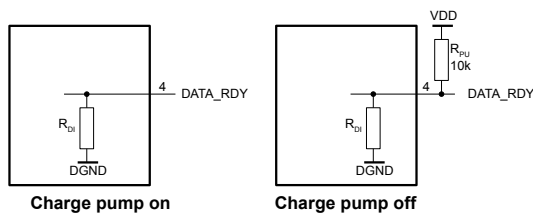


Figure 8: Charge pump operation

Important: Do not short DATA_RDY with VDD.

5. Imager operation

5.1. General remarks

The epc90x line imager chip series is based on a backside illumination technology (BSI). The image is taken from the backside of the chip, whereas the electrical circuits and the pins are on the frontside. Thus, the chip is flip-chip mounted to the PCB in order to expose the backside to the incoming light.

It is not possible with BSI to shield the photosensitive area with an integrated, electrically controlled shutter when there no light shall be detected. In other words, the pixel CCD is continuously photo-sensitive and collects charge generated by the detected photons (unwanted exposure). Thus, the CCD must be flushed or erased by the unwanted charge before an image can be acquired.

READ Pulse - The pulse applied to pin READ to initiate the read-out of a frame.

READ Clock - The clock applied to pin READ to read out the frame (after the Read Pulse).

5.2. Single frame acquisition

After the exposure time defined by the user, the charge collected in the CCD is shifted into an area which is not photo-sensitive. This area is called frame store. The following diagram shows this operation.

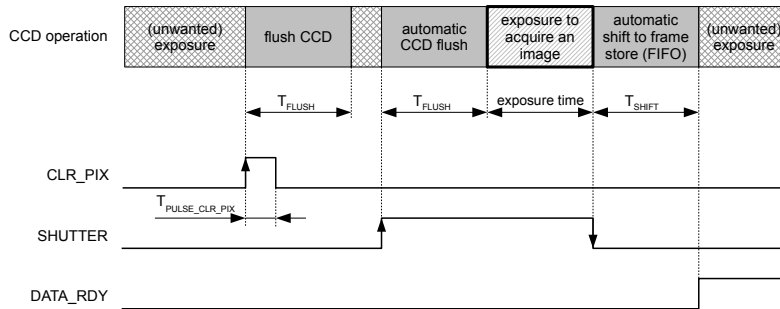


Figure 9: Image acquisition timing

The acquisition of a frame is controlled by a pulse on the SHUTTER pin (see Figure 9). The rising edge triggers the internal flush operation to erase the CCD from any unwanted electrons prior to the exposure. The exposure starts automatically after the flush operation is completed. The CCD collects electrons thereafter as long as the SHUTTER pin is high. Upon the falling edge of SHUTTER, the charge collected in the CCD pixel field is shifted to the CCD frame store which is an area which is not photo-sensitive (see (1) in Figure 10). As soon as the frame is ready for read-out, the signal DATA_RDY goes high. The image is ready to be readout as described in section 5.4

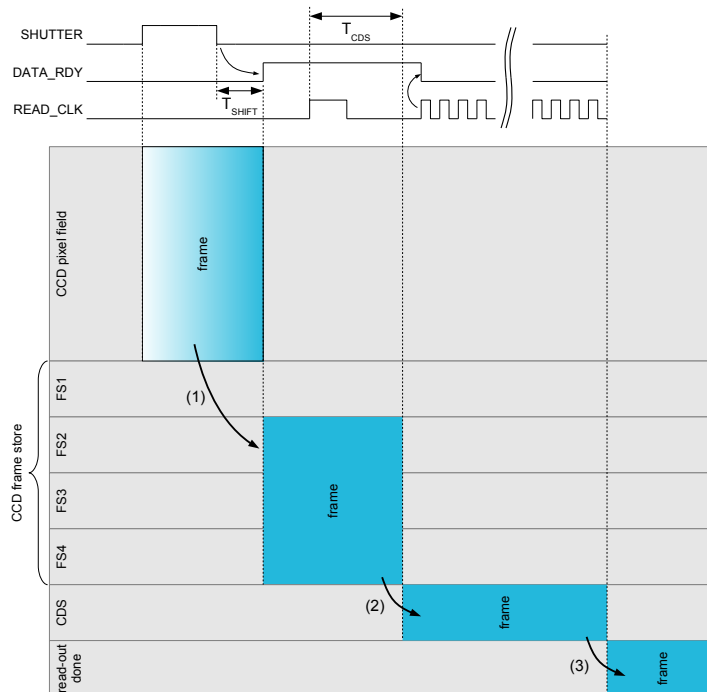


Figure 10: Example of single-frame acquisition and read-out

It is to note that the CCD continues to be photo-sensitive during the shift operation i.e. for a time T_{SHIFT} after the falling edge of SHUTTER.

5.3. Multi frame acquisition

Up to 4 images can be acquired and stored in the frame store in a fast sequence without intermediate read-out. The frame store is organized in 4 frame store elements (FS1-FS4), thereby each frame store element can store one frame/image. The first captured image initially occupies 3 frame store elements as for a single-frame acquisition (see section 5.2 and Figure 10). epc90x automatically detects a multi-frame acquisition when detecting the second SHUTTER signal without prior read-out. Upon the second shutter, the first image is shifted to a single frame store element (see (2) in Figure 11). The frames are shifted from the pixel field to the frame store as a FIFO: The first captured image is the first one to read out. The read-out is described in more detail in section 5.4. As soon as 4 frames have been captured without prior read-out, at least one read-out has to be issued prior the next shutter in order to make FS1 available again. Excessive shutter pulses are ignored.

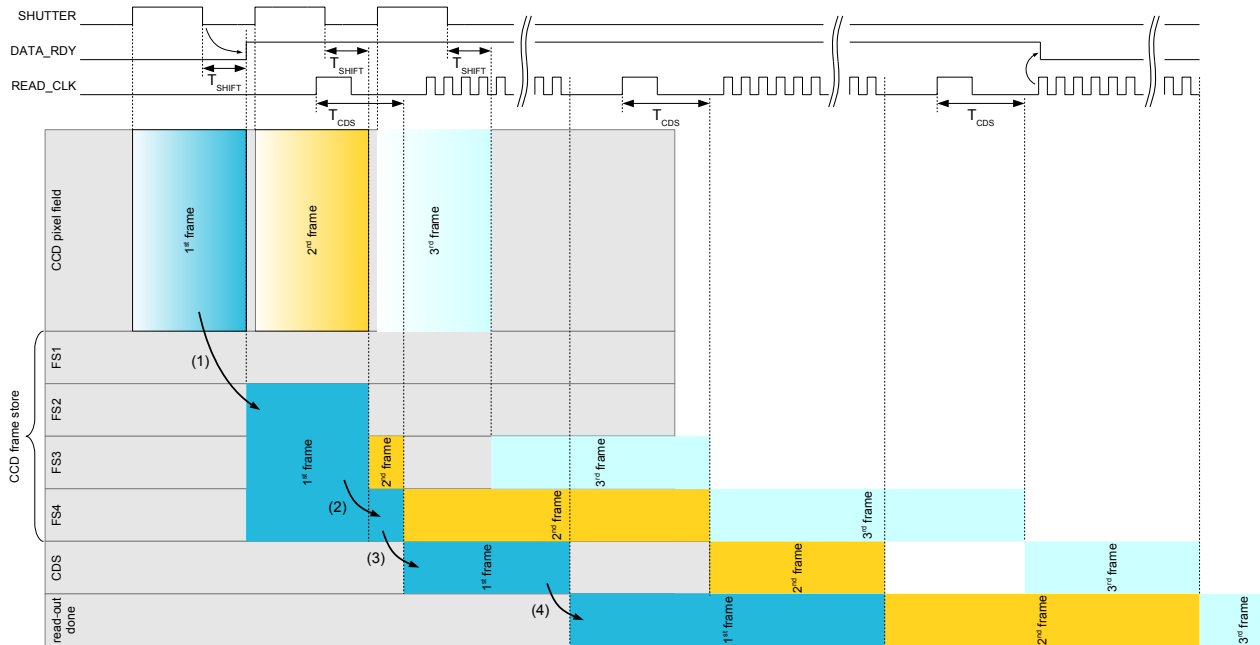


Figure 11: Multi-frame acquisition and read-out

5.4. Image readout

After one or more images have been captured, the first image (FIFO) can be read out through the interface on the pins VIDEO_P and VIDEO_N. The read-out is controlled by the READ pin. The following timing diagram shows its usage:

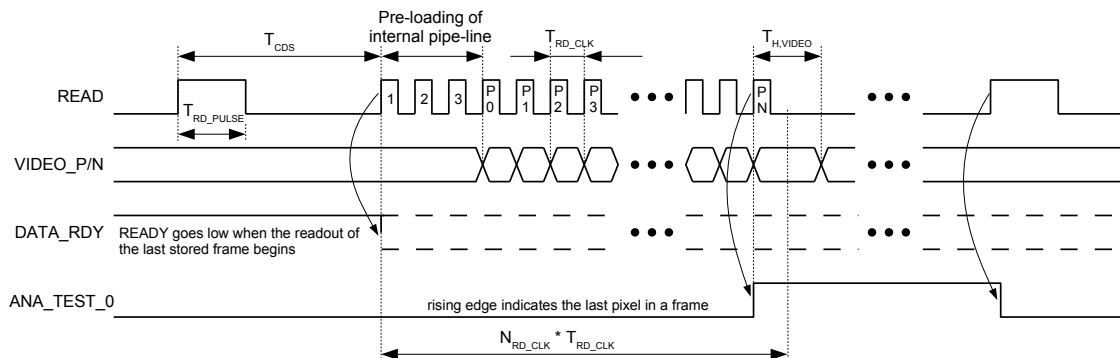


Figure 12: Image readout timing of one frame

The first pulse of a read sequence applied to pin READ is a Read Pulse and must have a duration of T_{RD_PULSE} . Upon this Read Pulse, the last frame in the frame store is converted pixel-wise from charge to voltage. This operation is called correlated double-sampling (CDS) and lasts for the time T_{CDS} . Following the Read Pulse, respecting a delay of at least T_{CDS} , Read Clock pulses are applied to the READ pin in order to transfer the pixel voltages to the VIDEO_P/N pins. The first 3 Read Clock pulses, designated with 1, 2 and 3 in Figure 12, are used to pre-load the pipeline. Thus the first 3 pixel voltage values on VIDEO_P/N can be ignored. The subsequent Read Clock pulses, designated with P0 ... PN in Figure 12, transfer the pixel voltage values through the video amplifier to the VIDEO_P/N pins.

After all pixels are read out, the output of the video amplifier is held stable for a time T_{H_VIDEO} or until the next Read Pulse, whatever occurs first. The transmission of the last pixel is indicated by a high state of the pin ANA_TEST_0 upon the last Read Clock pulse rising edge. ANA_TEST_0 goes low again upon the following rising edge at READ.

Any subsequent pulse of duration T_{RD_PULSE} is interpreted as a Read Pulse and thus a new read-out sequence is initiated.

The signal DATA_RDY remains high as long as there is at least one frame stored in the CCD frame store. If no more frames are stored except the one that is currently read out, the signal DATA_RDY goes to low state on the first positive Read Clock edge (see Figure 12). If no frame is stored, the chip does nothing upon a Read Pulse.

IMPORTANT

- Differential mode only: The last pixel is a dummy pixel and must be read for correct imager operation.
- It is important to sample the analog output signal of the video amplifier just before the rising edge of the next read pulse. This time point allows the readout circuits and the video amplifier to be fully settled. Also at this time point, the lowest possible readout noise can be achieved.
- The following time periods shall never overlap in any multi frame acquisition or by parallel reading during exposure: T_{FLUSH} with T_{CDS} and T_{SHIFT} with T_{CDS} . Refer for these signal to Figure 9 and Figure 12.
- At read clock frequencies above 20MHz, "ghost" signals in pixel_{i+4} pixel_{i+8} will become approximately as follows:

Read clock in MHz	Lag in % of illuminated pixel	
	4 th Pixel	8 th Pixel
20	10%	0%
40	35%	10%
50	45%	20%
54	50%	25%

Table 4: Image lag at high frequency readout

A software compensation algorithm is available to reduce this effect.

5.5. Flush

As explained in section 5.2, the imager is continuously photosensitive. So it continuously converts incoming light into charge. If the pixel field is not flushed periodically, excessive charge can be generated which may spill over from the pixel field to neighboring circuits, e.g. the frame store buffers. Thus, periodic flushing by applying a CLR_PIX pulse during the time no images are acquired is highly recommended, at least with a periodicity of $T_{PERIOD,FLUSH}$ (refer to section 3.3). However, the need to do so depends on how much light is received and how long is the time between two SHUTTER pulses.

It is recommended to evaluate the setup first before the system software is implemented. During evaluation, one measure of the charge generated in the pixel by applying a SHUTTER signal with the length of the time between the intended acquisition of two images shall be executed. If the maximal pixel value exceeds 90% of full well (= 90% of output swing), it is highly recommended to place additional CLR_PIX pulses during the time where no image acquisition takes place to flush the pixel field and frame store.

A pulse on SHUTTER is ignored if it is issued within T_{FLUSH} after the rising edge of CLR_PIX. If a rising edge on CLR_PIX occurs while SHUTTER is high or during the subsequent internal shift period T_{SHIFT} , the pulse on CLR_PIX is ignored.

In power-down mode, the CCD is not photo-sensitive and therefore no charge is collected. The transition from power-down to operation flushes the CDD and the frame store automatically.

The frames stored in the pixel field and the frame store can be erased simultaneously by a pulse on CLR_DATA with a minimum pulse width of T_{PULSE,CLR_DATA} . The clear operation is triggered by the rising edge of CLR_DATA. After the frame store and the pixel field are cleared, the chip is ready to acquire new images.

A rising edge on CLR_DATA also aborts an on-going read-out and a new image acquisition can be initiated immediately. As long as DATA_RDY is not asserted (upon the new image acquisition), the read-out of the frame in the CDS can be continued without any impact on the frame (for multi-frame operation see section 5.3)

A rising edge of CLR_DATA during a shift operation might be ignored and thus shall be avoided. It is allowed to assert SHUTTER and CLR_DATA at the same time.

Please note that the frame store buffers also collect charge even if there is no operation with the CCD. This is due to dark current which can also flow into the frame store buffer elements. Thus, the frame store buffer should also be cleared (erased) regularly.

6. Various features

6.1. Temperature sensor

There are two temperature sensors on chip. One on each side of the pixel array. They are off by default and can be turned on through I2C (see Table 21). The temperature sensors provide uncalibrated values with an offset ($OFFSET_{TEMP}$) and a gain ($GAIN_{TEMP}$). Thus, calibration is needed to allow absolute temperature measurements. Calibration can take place during manufacturing of the system by applying one or two reference temperature/s and storing the calibration value in a non-volatile memory e.g. in the MCU.

The temperature sensors can be read through the I2C interface registers TEMP_SENSE_0/1 (refer to Chapter 8.8).

6.2. Power-down

The chip can be forced into power-down mode to reduce the power consumption.

PWR_DOWN	Description
L	Operation
H	Power-down mode activated

If the chip is forced to power-down while frames are still stored on the IC, these frames are lost with power-down. When PWR_DOWN is asserted during an acquisition or transmission, the current operation is finished before the chip goes to power-down. When the power-down mode is de-activated, the IC needs T_{PWR_UP} to be back in functional mode. When PWR_DOWN goes to low state, the pixel array is automatically flushed. In power-down mode, no charge is collected by the CCD.

6.3. Oscillator clock trimming

The epc90x chip has an oscillator which controls the operation of the chip. The typical frequency is approx. 36MHz (refer to chapter 3.3). The internal clock oscillator frequency has an impact on the max. frame rate.

To measure this frequency in order to apply an optimized timing, the following procedure can be used:

1. Apply CLR_DATA
2. Apply SHUTTER for longer than T_{FLUSH} , e.g. 1µs
3. Measure the time from the falling edge of SHUTTER until the rising edge of DATA_RDY (T_{SHIFT})

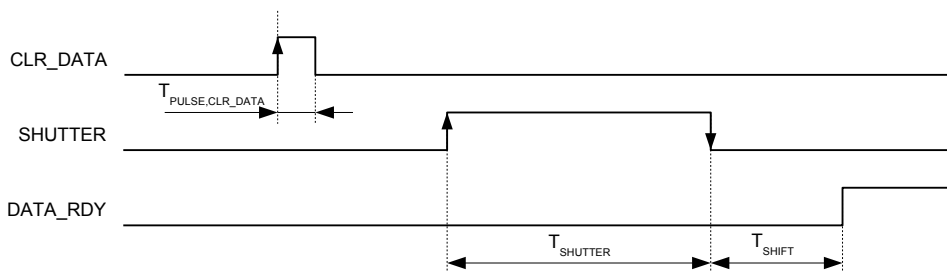


Figure 13: Sequence to measure internal clock frequency

Since T_{SHIFT} needs 24 to 26 clock cycles ($n * \text{ClockCycles}$), the frequency of the internal oscillator can be calculated according to the following formula:

$$F_{OSC} = \frac{n * \text{ClockCycles}}{T_{MEAS}}$$

E.g. if the measured time is 600ns, the oscillator frequency is between 40 and 43.3MHz. If the clock frequency shall be acquired more accurate, multiple measurements of T_{MEAS} shall be acquired and the average of these samples shall be used in the above formula. The clock frequency can be trimmed by setting a configuration register according to the description in Table 15 and 16.

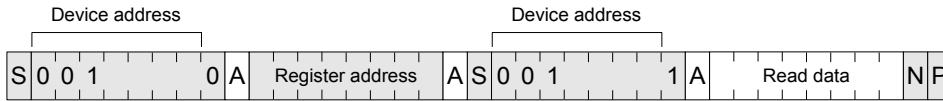
6.4. Reset

The epc90x can be reset by the following mechanisms:

- Disconnecting and reconnecting the power supply
- Reset command through I2C (refer to section 7.1.6)

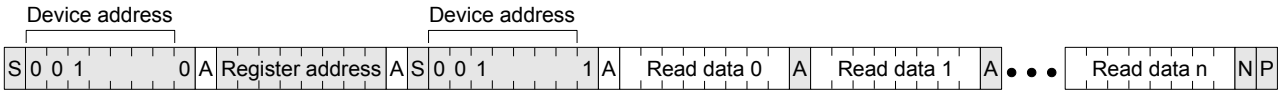
7.1.4. Single-byte read

During a single-byte read, only one register is read. After the device address is transmitted, the master has to transmit the register address. After addressing the epc90x IC with a read-command, it transmits the read data. The access is terminated with a NACK and a STOP by the master.



7.1.5. Multi-byte read

During a multi-byte read operation the master transmits the device address and the address of the first register to be read. Afterwards, the epc90x is addressed with a read command. It then transmits data bytes until the master applies NACK and a STOP.



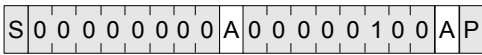
Registers reside in a non-consecutive address space. Reading to a unused address will return no useful data.

7.1.6. Software reset



A software reset has the same effect like a power-up reset. E.g. the chip uses the configuration as given by the configuration pins. Also, all trimming parameters are reset to the initial values.

7.1.7. Device address sampling



The device address pins CS0 and CS1 are sampled during power-up. They can be re-sampled by applying this command.

7.1.8. Setup latency

The new register value becomes active with the falling edge of the last bit transmitted.

7.2. I2C bus timing

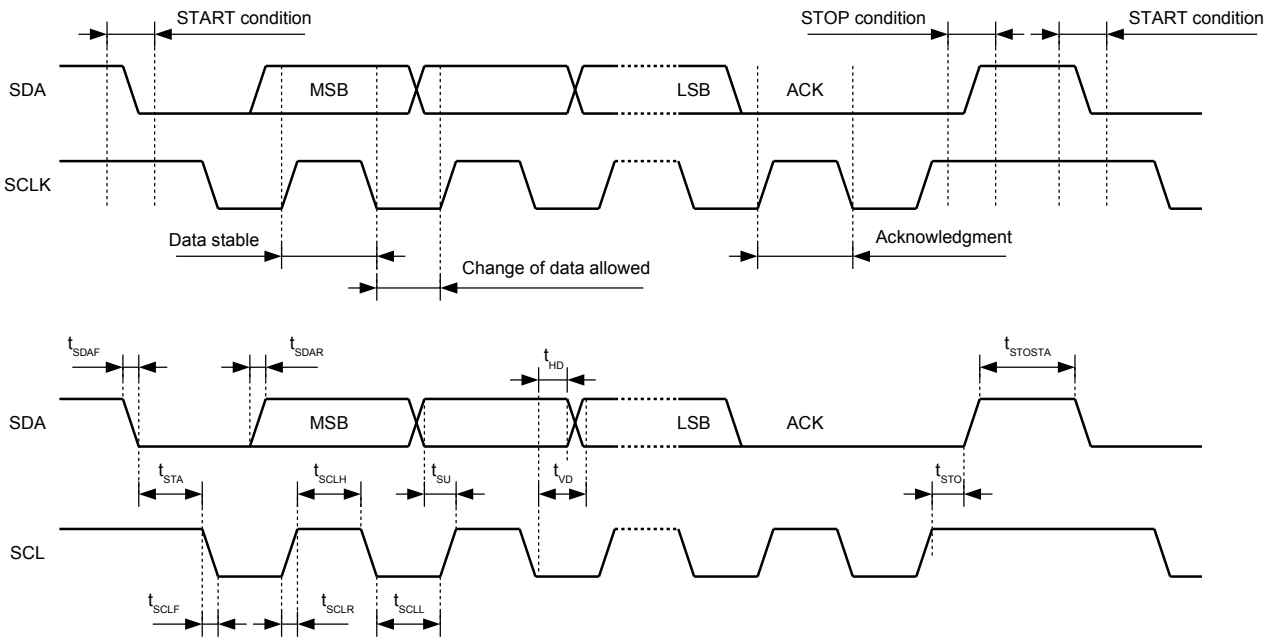


Figure 14: I²C bus timing, top: Basic communication sequence, bottom: Timing parameters

Symbol	Parameter	Min.	Max.	Units
f _{SCL}	I ² C data rate		400	kbit/s
t _{SCLL}	SCL clock low time	1.3		µs
t _{SCLH}	SCL clock high time	0.6		µs
t _{SU}	SDA setup time	100		ns
t _{HD}	Data hold time	0		ns
t _{VD}	Data valid time		900	ns
t _{SDAR} t _{SCLR}	SDA and SCL rise time		300	ns
t _{SDAF} , t _{SCLF}	SDA and SCL fall time		300	ns
t _{STA}	Start condition hold time	0.6		µs
t _{STO}	Stop condition setup time	0.6		µs
t _{STOSTA}	Stop to start condition time (bus free)	1.3		µs
C _b	Capacitive load for each bus line		400	pF
t _{SP}	Pulse width of the spikes that are suppressed by the analog filter		50	ns

Table 5: I²C bus timing: Timing parameters (FM+)

8. Register description

Address	Register name	Ref.	Description
0x00	ACQ_TX_CONF_I2C	Table 7	Imager control
0x01	BW_VIDEO_CONF_I2C	Table 8	Video amplifier bandwidth
0x02	MISC_CONF	Table 11	Various settings
0x90	OSC_TRIM_REG	Table 15	Oscillator trimming (fine)
0x94	VIDEO_GBW_SEL_REG	Table 9	Video amplifier bandwidth, noise and current consumption
0xA0	TEMP_SENS_L_LSB	Table 18	LSB of left temperature sensor
0xA1	TEMP_SENS_L_MSB	Table 19	MSB of left temperature sensor
0xA2	TEMP_SENS_R_LSB	Table 20	LSB of right temperature sensor
0xA3	TEMP_SENS_R_MSB	Table 21	MSB of right temperature sensor
0xA4	TEMP_SENS_CONF	Table 22	Temperature sensor configuration
0xB0	I2C_ERROR_IND	Table 24	I2C error flag
0xD6	FORCE_ANA_CTRL_SIGS	Table 13	Analog control settings, e.g. power control
0xD7	OSC_TRIM_RANGE_REG	Table 17	Oscillator trimming (coarse)
0xFF	CHIP_REV_NO_REG	Table 25	Chip revision

Table 6: Register map accessible by the I2C interface

IMPORTANT NOTES:

- “n/a” means “not applicable”. Do not modify these register bits. Thus, read first the register, modify the required bits and then write back the modified register value.
- Do not write to other addresses than listed in Table 6. If accidentally a write has been occurred to a register address not in the list above, unexpected behavior can occur. A hardware reset brings the imager back to factory settings.
- Default values are indicated as bold letters§
- In the tables below, allowed operations are:
 - R: Read
 - W: Write
 - WP: Write protected

8.1. Imager control

0x00	ACQ_TX_CONF_I2C							
Bit no.	7	6	5	4	3	2	1	0
Bit name	n/a	n/a	MOD_B		GAIN		MOD_R	RD_DIR
Operation	n/a	n/a	R/W		R/W		R/W	R/W
Default	0	0	0	1	0	1	0	0

Table 7: Description of register ACQ_TX_CONF_I2C

MOD_B:	epc902 / epc904:	00 (no single ended mode)
	epc903 / epc905:	10
GAIN:	Video amplifier gain	00: 2 01: 1 10: 4
MOD_R:	epc902 / epc903:	0
	epc904 / epc905:	1
RD_DIR:	Read direction	0: Left to right (from 0 to highest pixel count) 1: Right to left (from highest pixel count to 0)

8.2. Video Amplifier bandwidth

0x01	BW_VIDEO_CONF_I2C							
Bit no.	7	6	5	4	3	2	1	0
Bit name	n/a	n/a	n/a	n/a	BW_VIDEO_1		BW_VIDEO_0	
Operation	n/a	n/a	n/a	n/a	R/W		R/W	
Default	0	0	0	0	0	1	0	1

Table 8: Description of register BW_VIDEO_CONF_I2C

BW_VIDEO_1/0:	1010:	Video bandwidth 1 MHz
	1000:	Video bandwidth 4 MHz
	0010:	Video bandwidth 8 MHz
	0101:	Video bandwidth 16 MHz

Notes

1. Refer also to section 3.7
2. The video bandwidth does not exactly match with the frequency values mentioned in Table 8. Please note that these values are approximative only.
3. Make sure MISC_CONF:RD_CONF_CTRL is set to 1
4. The settings of this register become active at the rising edge of a Read pulse
5. The use of this register overwrites the values set by the configuration pins (refer to Table 2 and Table 3)

8.3. Video amplifier bandwidth, noise and current consumption

0x94	VIDEO_GBW_SEL_REG							
Bit no.	7	6	5	4	3	2	1	0
Bit name	n/a	n/a	n/a	n/a	n/a	n/a	GBW_SEL_DI	
Operation	n/a	n/a	n/a	n/a	n/a	n/a	R/W	
Default	0	0	0	0	0	0	0x3	

Table 9: Description of register VIDEO_GBW_SEL_REG

The bandwidth, noise and current consumption of the video amplifier is adjustable with this register as listed in Table 10. These settings regarding the video bandwidth are on top of the settings in Chapter 8.2 E.g. if the Video bandwidth is set to 4 MHz (in Table 8), and the GBW_SEL_DI is set to 0x01, the resulting bandwidth is 2 MHz. Please note that these values are approximative only.

GBW_SEL_DI	Relative video amplifier bandwidth	Relative video amplifier current consumption	Relative read noise
00	25%	lowest	lowest
01	50%		
10	75%		
11	100%	highest	highest

Table 10: Bandwidth selection and bias current trimming (approx. values)

8.4. Configuration control, video amplifier on/off

0x02	MISC_CONF							
Bit no.	7	6	5	4	3	2	1	0
Bit name	n/a	n/a	n/a	n/a	n/a	VIDEO_AMP_PD_OVR_EN	VIDEO_AMP_PD_OVR	RD_CONF_CTRL
Operation	R/W	R/W	R/W	R/W	R/W	R/W	R/W	R/W
Default	1	0	0	1	1	0	0	0

Table 11: Description of register MISC_CONF

Register Name	Description	1	0
VIDEO_AMP_PD_OVR_EN	Enable/disable register bit VIDEO_AMP_PD_OVR	enabled	disabled
VIDEO_AMP_PD_OVR	Video amplifier power down. This bit is only effective if register bit VIDEO_AMP_PD_OVR_EN is set	Video amp off	Video amp on
RD_CONF_CTRL	Configuration control	By configuration registers	By configuration pins

Table 12: Description of register setting MISC_CONF

8.5. Video amplifier SE/Diff, charge pump on/off, 5V regulator on/off

0xD6	FORCE_ANA_CTRL_SIGS							
Bit no.	7	6	5	4	3	2	1	0
Bit name	n/a	n/a	n/a	n/a	AMP_OVR_EN	AMP_OVR	VDD5V0_PD	CP_PD
Operation	R/WP	R/WP	R/WP	R/WP	R/WP	R/WP	R/WP	R/WP
Default	0	0	1	0	0	0	0	0

Table 13: Description of register FORCE_ANA_CTRL_SIGS

Bit Name	Description	1	0
AMP_OVR_EN	Control of the video amplifier mode selection AMP_OVR	enabled	disabled
AMP_OVR	Video amplifier mode selection (AMP_OVR_EN=1)	Differential	Single-ended
VDD5V0_PD	Power control of the 5V regulator	Regulator off	Regulator on
CP_PD	Power control of the charge pump	Charge pump off	Charge pump on

Table 14: Description of register setting FORCE_ANA_CTRL_SIGS

Notes

- FORCE_ANA_CTRL_SIGS is write-protected (WP). The following example sequence turns the regulator and the charge pump off:
 - Write address 0xD0: 0x4A //unlock register write protection
 - Write address 0xD1: 0x66 //unlock register write protection
 - Write Address 0xD6: FORCE_ANA_CTRL_SIGS = 0x23 //disable charge pump and 5V regulator
- No other read or write access is allowed in between the sequence above
- After this sequence, the register FORCE_ANA_CTRL_SIGS is automatically locked
- AMP_OVR = 0 is not valid for epc902 / epc904

8.6. Oscillator trimming (fine)

0x90	OSC_TRIM_REG							
Bit no.	7	6	5	4	3	2	1	0
Bit name	n/a	n/a	n/a	n/a	OSC_TRIM			
Operation	n/a	n/a	n/a	n/a	R/W			
Default	0	0	0	0	0x0			

Table 15: Description of register OSC_TRIM_REG

The trim range of OSC_TRIM is approx. 1.2 MHz per step:

Bit no.				Trim Value (MHz)
3	2	1	0	
1	0	0	0	-9.6
1	0	0	1	-8.4
1	0	1	0	-7.2
1	0	1	1	-6.0
1	1	0	0	-4.8
1	1	0	1	-3.6
1	1	1	0	-2.4
1	1	1	1	-1.2
0	0	0	0	0.0
0	0	0	1	+1.2
0	0	1	0	+2.4
0	0	1	1	+3.6
0	1	0	0	+4.8
0	1	0	1	+6.0
0	1	1	0	+7.2
0	1	1	1	+8.4

Table 16: Oscillator trimming

8.7. Oscillator trimming (coarse)

0xD7	OSC_TRIM_RANGE_REG							
Bit no.	7	6	5	4	3	2	1	0
Bit name	n/a	n/a	n/a	n/a	n/a	n/a	n/a	OSC_TRIM_RANGE_UP
Operation	n/a	n/a	n/a	n/a	n/a	n/a	n/a	R/W
Default	0	0	0	0	0	0	0	0

Table 17: Description of register OSC_TRIM_RANGE_REG (available from revision number 0x14)

OSC_TRIM_RANGE_UP Defines oscillator trim range:
0: default oscillator trim range
 1: oscillator frequency increased by 25%

8.8. Temperature sensors read

There are four registers which hold the current temperature values of the two temperature sensors. Once one of these addresses is read, all other temperature sensor registers are frozen until all four registers are read. The read sequence of these registers is not important.

The left temperature sensor is located near pixel 0, the right one near pixel 1023.

8.8.1. Left temperature sensor

0xA0	TEMP_SENSE_L_LSB							
Bit no.	7	6	5	4	3	2	1	0
Bit name	TEMP_L[7:0]							
Operation	R							
Default	0x0							

Table 18: Description of register TEMP_SENSE_L_LSB

0xA1	TEMP_SENSE_L_MSB							
Bit no.	7	6	5	4	3	2	1	0
Bit name	n/a	n/a	n/a	TEMP_L[12:8]				
Operation	n/a	n/a	n/a	R				
Default	0	0	0	0x0				

Table 19: Description of register TEMP_SENSE_L_MSB

8.8.2. Right temperature sensor

0xA2	TEMP_SENSE_R_LSB							
Bit no.	7	6	5	4	3	2	1	0
Bit name	TEMP_R[7:0]							
Operation	R							
Default	0x0							

Table 20: Description of register TEMP_SENSE_R_LSB

0xA3	TEMP_SENSE_R_MSB							
Bit no.	7	6	5	4	3	2	1	0
Bit name	n/a	n/a	n/a	TEMP_R[12:8]				
Operation	n/a	n/a	n/a	R				
Default	0	0	0	0x0				

Table 21: Description of register TEMP_SENSE_R_MSB

8.9. Temperature sensors control

0xA4	TEMP_SENS_CONF							
Bit no.	7	6	5	4	3	2	1	0
Bit name	n/a	n/a	MEAS_RATE_CONF		ENABLE_R	ENABLE_L	PD_CONF_R	PD_CONF_L
Operation	n/a	n/a	R/W		R/W	R/W	R/W	R/W
Default	0	0	0	0	0	0	1	1

Table 22: Description of register TEMP_SENS_CONF

Register Name	Description	1	0		
MEAS_RATE_CONF	Configure the measurement rate of the temperature sensors: 00: 10 measurements per second 01: 1 measurement per second 10: 1 measurement every 10 seconds Note: A change of the measurement rate becomes effective after the temperature sensor has been disabled and enabled again				
ENABLE_R	ENABLE_R	ENABLE_L	PD_CONF_R	PD_CONF_L	Description
ENABLE_L	0	0	1	1	Both sensors off
PD_CONF_R	1	1	0	0	Both sensors on
PD_CONF_L	1	0	0	1	Only right sensor on
	0	1	1	0	Only left sensor on

Table 23: Description of register setting TEMP_SENS_CONF

8.10. I2C error flag

0xB0	I2C_ERROR_IND							
Bit no.	7	6	5	4	3	2	1	0
Bit name	n/a	n/a	n/a	n/a	n/a	n/a	n/a	I2C_ERR
Operation	n/a	n/a	n/a	n/a	n/a	n/a	n/a	R
Default	n/a	n/a	n/a	n/a	n/a	n/a	n/a	0

Table 24: Description of register I2C_ERROR_IND

I2C_ERR

This bit is set if the I2C controller fails to service a register operation. In error condition, the affected read operation may return wrong data or the affected write operation may be ignored. This bit is automatically reset after a read cycle.

8.11. Chip revision

0xFF	CHIP_REV_NO_REG							
Bit no.	7	6	5	4	3	2	1	0
Bit name	CHIP_REV_NO							
Operation	R							
Default	0	0	1	0	0	0	0	1

Table 25: Description of register CHIP_REV_NO_REG

9. Application information

Referring to Figure 15 and Figure 16, please note the following:

- The GND pins can be connected together, preferably to a plane / star connection. Refer also to section 9.4.3
- The video amplifier has separate supply pins VDD_OA and GND_OA due to its fast switching currents. It is important to block this power supply pins with low ESR capacitors as close as possible to the chip in order to avoid noise at the video output due to supply voltage bouncing.
- The voltage level applied to VDD_OA must be the same as on pin VDD. Otherwise the IC can be damaged due to latch-up.

9.1. Differential mode

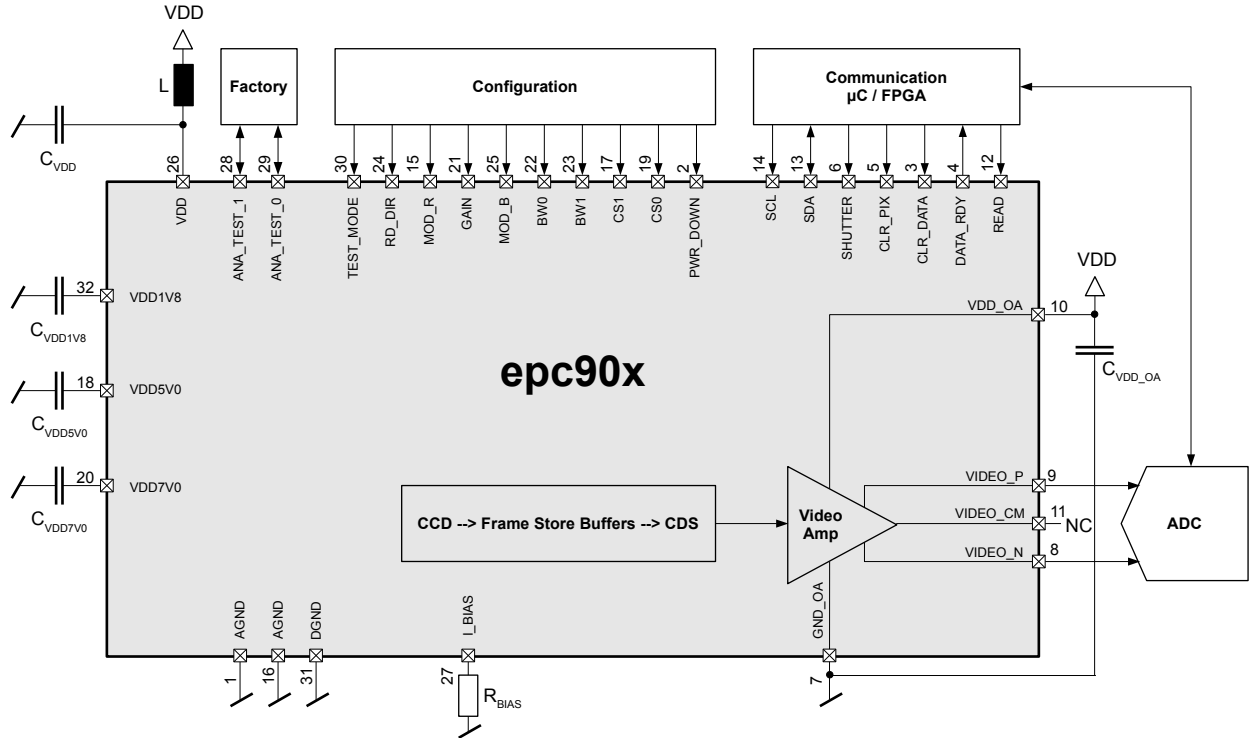


Figure 15: Differential mode application diagram

Pin 11 (VIDEO_CM) can be left open. The IC sets this pin to VDD/2 which is the offset voltage of the VIDEO_P and VIDEO_N signal. However, it is possible to apply a voltage source at VIDEO_CM to control the common mode voltage of the output signal. Make sure that this is a low noise/low ripple source and add a 1µF low ESR blocking capacitor as close as possible to pin 11. The voltage at VIDEO_CM must be as defined in the table under section 3.1 $V_{CM,D}$.

Illumination	VIDEO_N	VIDEO_P	VIDEO_P – VIDEO_N (typ.)
Dark voltage	$V_{VIDEO_CM} + 0.4V$	$V_{VIDEO_CM} - 0.4V$	-0.8V
Maximum video output	$V_{VIDEO_CM} - 0.6V$	$V_{VIDEO_CM} + 0.6V$	1.2

Table 26: Video amplifier output in differential mode

9.2. Single ended mode

(for epc903 / epc905 only)

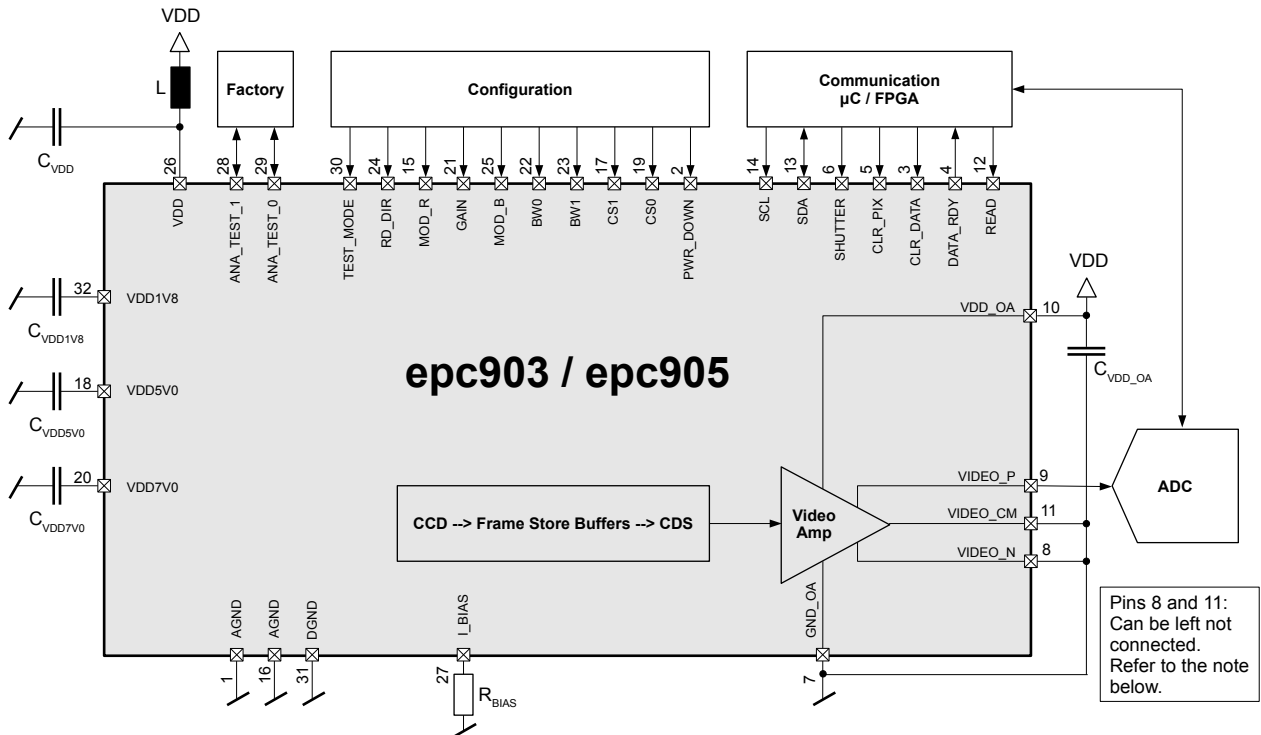


Figure 16: Single ended mode application diagram

If VIDEO_N and VIDEO_CM are tied to GND at power-up or RESET, single-ended mode is enabled. The output signal is available at VIDEO_P.

Illumination	VIDEO_P (typ.)
Dark voltage	0.4V
Maximum video output	2.0V

Table 27: Video amplifier output in single-ended mode

9.3. External components

The external components in Figure 15 and Figure 16 shall be as follows:

Parameter	Description	Value	Units	Tolerance	Comments
R _{BIAS}	Bias resistor	56k	kΩ	±1%	Temperature coefficient max. ±100ppm/K
C _{VDD1V8}	Decoupling capacitor	1.0	μF	±20%	low ESR
C _{VDD5V0} , C _{VDD7V0}	Decoupling capacitors	2.2	μF	±20%	low ESR
C _{VDD} , C _{VDD_OA}	Decoupling capacitors	1.0	μF	±20%	low ESR
L	Decoupling inductor	600	Ω		@100MHz, e.g. Taiyo Yuden BK1005HR601-T

9.4. Low noise operation

9.4.1. Charge pump noise

The internal charge pump generates some noise, especially in single-ended mode. The noise performance can be optimized by turning off the charge pump and supplying the chip with an external 5V supply. Refer to section 10.2

9.4.2. Video amplifier noise

Another noise source is the video amplifier which can be used in two different modes. Single ended mode is the lower noise operation mode. Thus, use the chip in single ended mode for low noise applications. In addition, operate the video amplifier at lowest possible bandwidth and lowest current consumption. Refer to 8.2 and 8.3

9.4.3. Layout recommendations

The epc90x line imager is a very high sensitivity analog/digital chip. Due to its high conversion gain, just a few electrons collected by coupling to signal lines close to the chip generate a significant voltage at the output. Thus, do not place any signal lines underneath the chip without shielding. It is highly recommended to place a stable AGND plane underneath the epc90x chip (on the top layer of the PCB) and not to place any signal tracks close to the chip.

Also very important is a clean noise-free power supply. Especially decouple the VDD from VDD_OA with capacitor so the output modulation of the video amplifier does not modulate the VDD of the chip. Make sure all the capacitors used for decoupling are low ESR types.

The READ signal line can also be a major source of noise or coupling to the output signal. Figure 17 shows a scope screen shot of such a coupling problem.

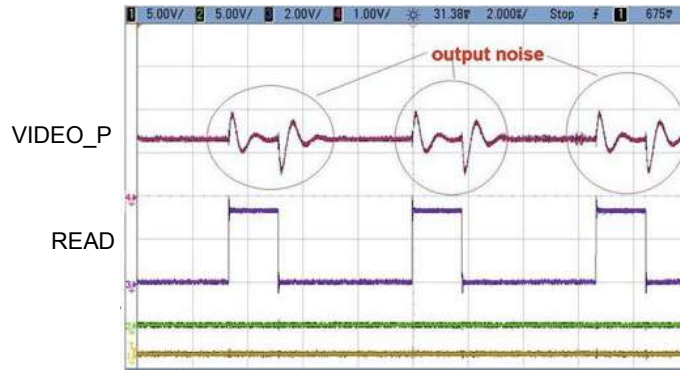


Figure 17: READ signal coupling to the output by a ground loop

The source of such problems is usually a ground loop. Especially if there is a significant distance 'd' as shown in Figure 18 (starting from a few cm only) between the video output of the epc90x chip and the input of the ADC. Care has to be taken that the layout of the GND lines is exactly like shown in Figure 18. **Make sure that the digital GND has a separate track as shown by the blue ground line!**

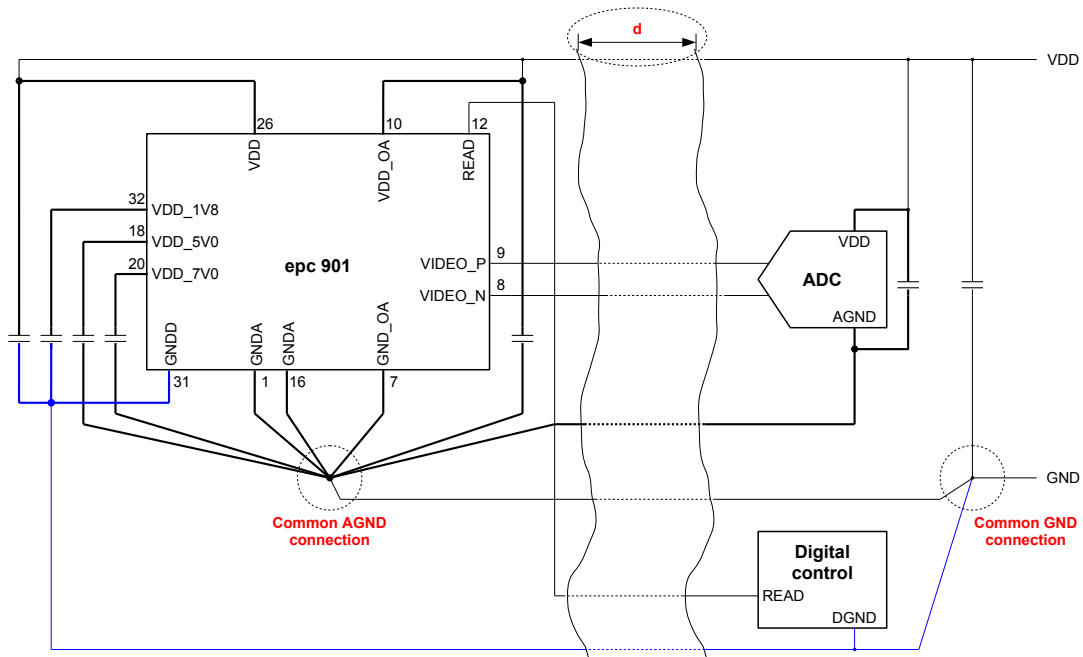


Figure 18: Recommended ground and power supply connections

Make also sure that the thick lines in Figure 18 are as short and as thick as possible.

10. Power consumption considerations

10.1. General considerations

There are several options to control the power consumption. However, a trade-off between performance and power consumption has to be considered. The following section describes the various options. The most power-consuming blocks are

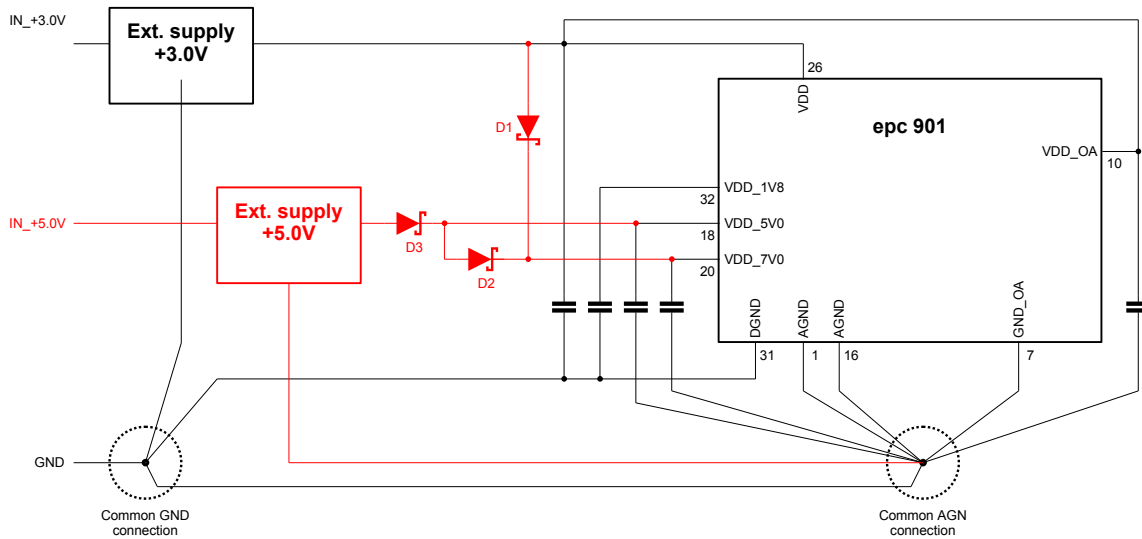
- Temperature sensors (approx. 3mA)
- Video amplifier (approx. 3.5mA)
- Charge pump and 5V regulator (approx. 13.5mA)

The wake-up time of the video amp is typ. 3µs only. Thus, in most applications it can be turned off during illumination in order to reduce the average power consumption.

10.2. Low power operation

The lowest possible power consumption of the epc90x can be achieved if it is supplied with 3V and 5V since the highest power consumption is the internal charge pump which generates the 5V from VDD. In this case, the chip-internal charge pump and the internal 5V regulator shall be turned off. The power consumption in this configuration is less than 20mW compared to 80mW in the standard mode. The following application information shows how this can be achieved. Follow carefully the instructions in order to avoid damage of the chip.

Use protection diodes according to circuit diagram below. The diodes have to be low voltage Schottky devices with a forward current of at least 100mA (i.e. BAT74).



Make sure that external 5V supply (VDD_5V0) is delayed by at least 100µs to the VDD.

1. Power up VDD (3V)
2. Wait for at least 100µs
3. Power up VDD_5V0

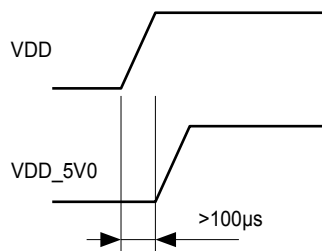


Figure 19: Power up sequence in low power configuration

11. Layout and packaging information

11.1. Mechanical dimensions

The packaging technology is a CSP with a uBGA. All measures which do not have an explicit tolerance are meant +/-0.001mm.

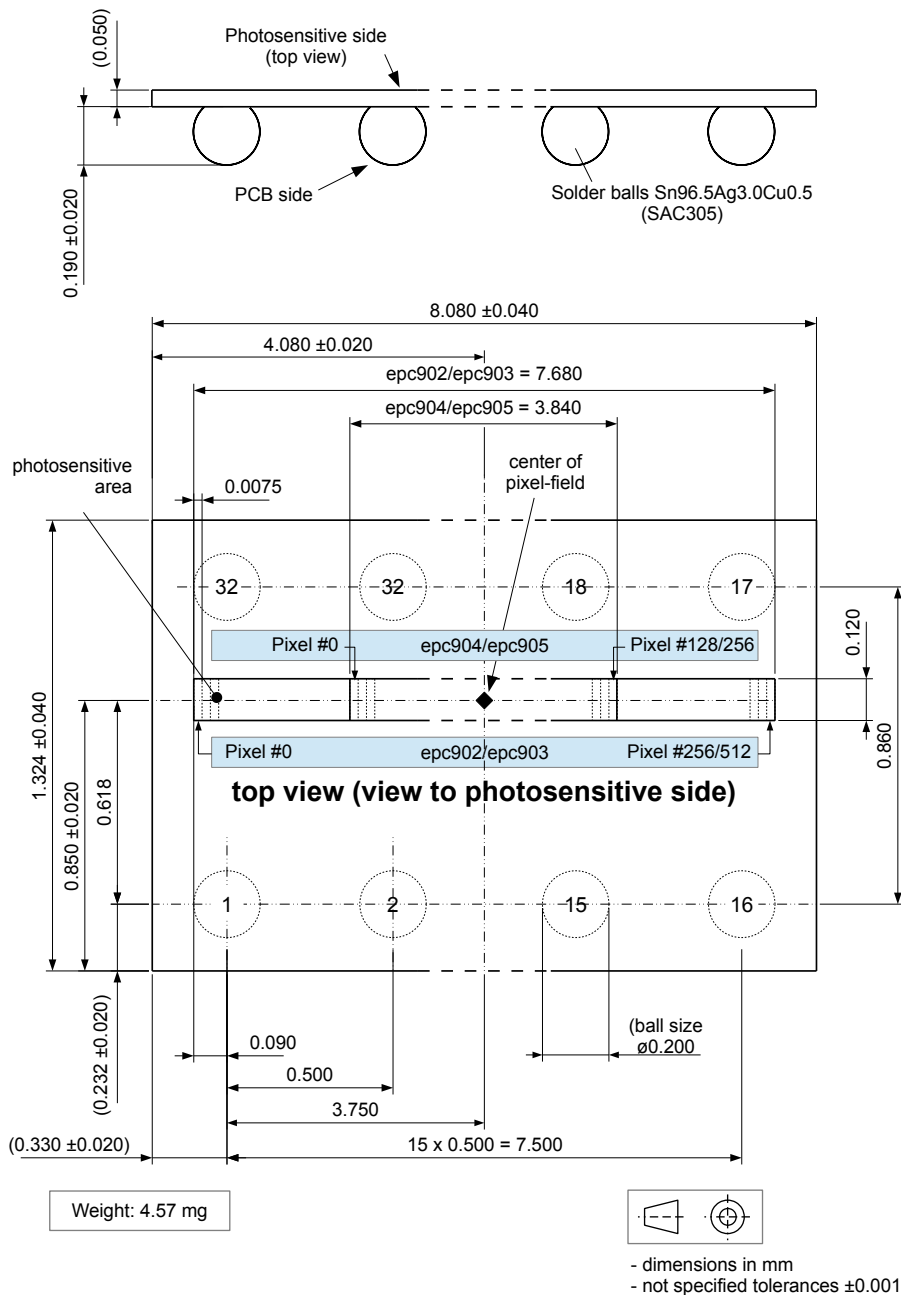


Figure 20: Mechanical dimensions

The photosensitive area is not marked neither on the front nor on the backside of the IC. As a visible reference, the metal ring of the IC can be used which is visible from the back side (solder ball side). Also from the front side (photosensitive area) it can be seen with a camera which is sensitive in the near infrared wavelength domain (950 .. 1150nm). Figure 21 shows the epc90x chip from the bottom side with view to the solder balls. Please note the location of pin 1 from bottom view.



Figure 21: Chip micrograph (bottom view)

11.2. PCB design and SMD manufacturing process considerations

The epc90x chip comes in a very small 32 pin chip scale package, the PCB layout should be made with special care. The silicon chip is small and light weight compared to its solder balls. It is highly recommended that all tracks to the chip should come straight from the side. A consequent symmetrical PCB layout design is highly recommended to achieve high production yield.

The pads and the tracks should also have exactly the same width. The tracks shall be covered by a solder resist mask in order to avoid drain of the solder tin alloy to the track.

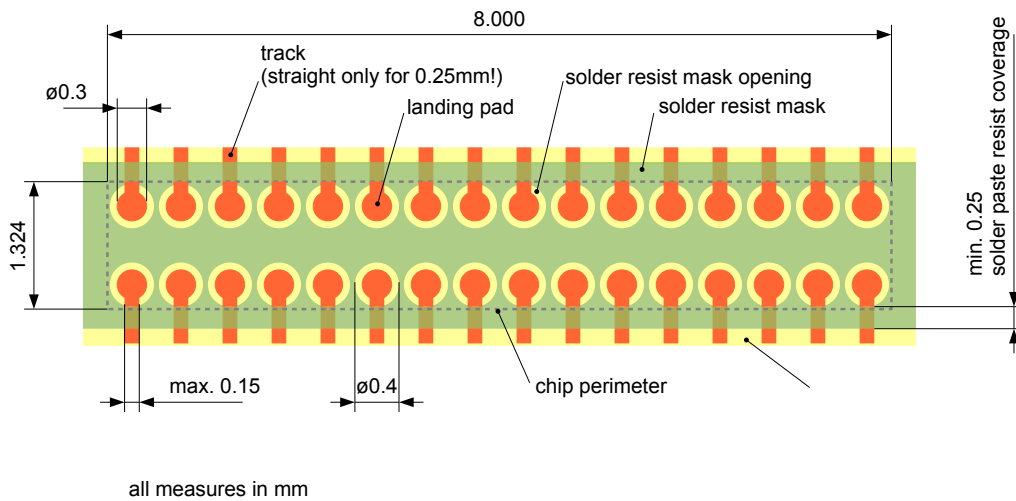


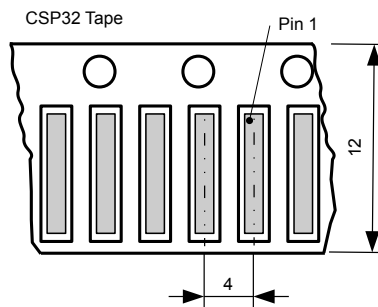
Figure 22: Recommended PCB layout

Underfill of the components reduces stress to the solder pads caused by e.g. temperature cycling or mechanical bending. The thermal and mechanical fatigue will be reduced and the longterm reliability will be increased. Underfill and underfill selection is application specific. It shall follow JEDEC-STD JEP150: Stress-Test-Driven Qualification of and Failure Mechanisms Associated with Assembled Solid State Surface- Mount Components.

Please refer to the application note AN08_Process-Rules_CSP_Assembly. Please follow carefully the recommendations in this application note to achieve a high manufacturing yield.

11.3. Tape & Reel Information

The devices are packed in tape on reel for automatic placement systems. The tape is wound on 178 mm (7 inch) or 330 mm (13 inch) reels and individually packaged for shipment. General tape-and-reel specification data are available in a separate data sheet and indicate the tape sizes for various package types. Further tape-and-reel specifications can be found in the Electronic Industries Association (EIA) standard 481-1, 481-2, 481-3.



ESPROS does not guarantee that there are no empty cavities. Thus, the pick-and-place machine should check the presence of a chip during picking.

11.4. Soldering and IC handling

Since the chip is only 50µm thick and has a high aspect ratio (length to width), a careful handling during the surface mount assembly process shall be taken in order to avoid mechanical damage. In addition to that, careful PCB layout is needed in order to achieve reliable assembly results with a high yield. Please refer to the application note AN08_Process-Rules_CSP_Assembly which contains most up to date and comprehensive information to these topics. This application note can be downloaded at www.espros.com/application-notes.

12. Ordering Information

Part Number	Part Name	Package	RoHS	Packaging Method
P100 860	epc902-CSP32-033	CSP32	Yes	Reel
P100 861	epc903-CSP32-033	CSP32	Yes	Reel
P100 862	epc904-CSP32-033	CSP32	Yes	Reel
P100 863	epc905-CSP32-033	CSP32	Yes	Reel

Table 28: Ordering information

Application notes can be downloaded from the ESPROS website at www.espros.com/downloads/09_Application_notes.

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